


<b>Search Notes</b>  	<b>Application/Control No.</b>  10559715	<b>Applicant(s)/Patent Under Reexamination</b>  TAN ET AL.
	<b>Examiner</b>  DAQUAN ZHAO	<b>Art Unit</b>  2621

SEARCHED			
Class	Subclass	Date	Examiner
386	248,252,254,255,257,258,259,260	5/20/2011	dz

SEARCH NOTES		
Search Notes	Date	Examiner
USPAT; USPGPUB; USOCR; EPO; JPO; DERWENT; IBM_TDB	9/21/2010	DZ

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
386	248,252,254,255,257,258,259,260	5/20/2011	dz

--	--